

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/070,209	<b>Applicant(s)/Patent under Reexamination</b> SAKANAKA ET AL.
	<b>Examiner</b> Patricia Leith	<b>Art Unit</b> 1655

INTERFERENCE SEARCHED.			
Class	Subclass	Date	Examiner